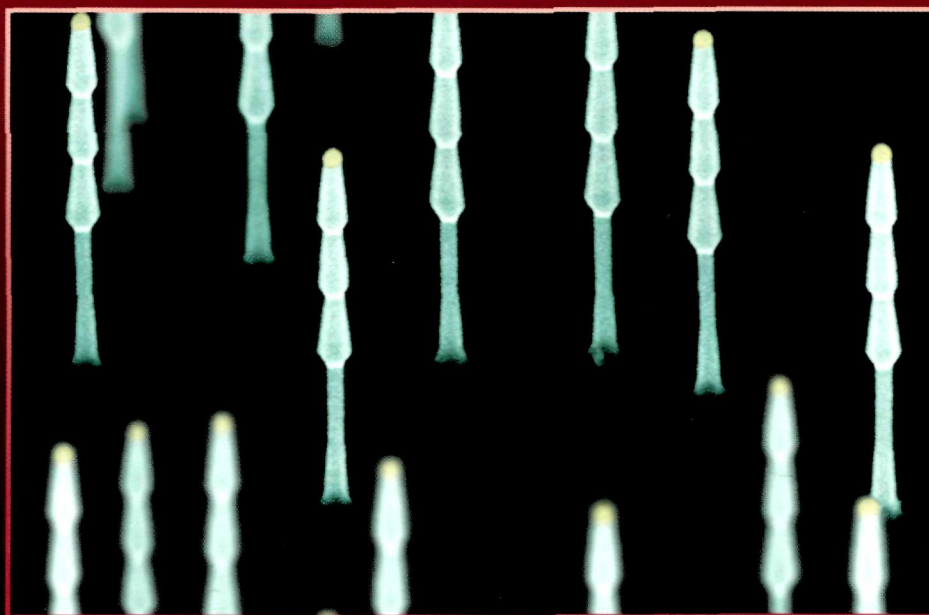


## Nanotechnology & Microelectronics: Materials, Processing, Measurement, & Phenomena



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**Review Article:**  
**Synthesis, Properties, and Applications of Silicon Nanocrystals**  
*-by Lorenzo Mangolini*

Papers from the 25th International Vacuum Nanoelectronics Conference



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## Materials, Processing, Measurement, and Phenomena

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